In Semiconductors
Together

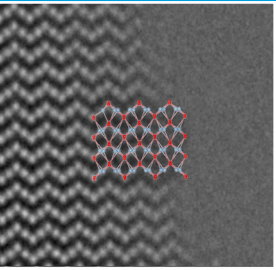
Hchip

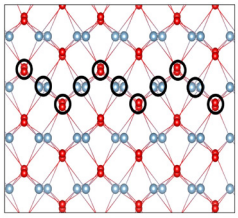
Hungarian Chip
Competence Centre



- Look Deeper!
- Explore!
- Understand!

ATOMIC-LEVEL STRUCTURAL ANALYSIS







A hands-on introduction to modern transmission electron microscopy (TEM) techniques for structural analysis using an advanced Themis TEM-EDS system.

WHAT WILL YOU LEARN?

- Electron microscopy imaging and analytical fundamentals
- Electron microscopy sample preparation
- Focused ion beam (FIB) thin-section preparation
- Atomic-resolution TEM imaging
- Electron diffraction analysis
- High-resolution elemental mapping
- Real-world industrial applications

2 × 45 MIN THEORY + 2 × 3 H LAB / MAX. 5 PEOPLE / HUNGARIAN & ENGLISH

Experience the technology in action! **www.hchip.hu**

PROJECT CONSORTIUM MEMBERS:

Bay Zoltán Research Centre

HUN REN Centre for Energy Research

BME Budapest University of Technology and Economics

PROJECT FUNDERS:

Chips JU

Program financed from the NRDI Fund

Magyarország Kormánya

Funded by the European Union

THE PROJECT IS IMPLEMENTED WITH THE SUPPORT OF THE EUROPEAN UNION. THE VIEWS AND OPINIONS EXPRESSED ARE SOLELY THOSE OF THE AUTHOR(S) AND DO NOT NECESSARILY REFLECT THOSE OF THE EUROPEAN UNION OR OF THE CHIPS JOINT UNDERTAKING AS THE GRANTING AUTHORITY. NEITHER THE EUROPEAN UNION NOR THE GRANTING AUTHORITY CAN BE HELD RESPONSIBLE FOR THEM.